

A Bayesian Analysis of Recognition Memory

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We present a Bayesian method for analyzing recognition memory experiments that determines our confidence that a substantive proportion of participants are best captured by an error-only or an error-plus-effect model. Consequently, positive evidence for the null hypothesis can be attained and conclusions cannot be driven by a minority of participants. Sample sizes need not be fixed in advance and the method is safe when N s are small. We use the method to demonstrate the null list length effect in recognition memory.